

**Search Notes****Application/Control No.**

10/017,268

**Examiner**

Srilakshmi K. Kumar

**Applicant(s)/Patent under Reexamination**

CROSS ET AL.

**Art Unit**

2629

**SEARCHED**

Class	Subclass	Date	Examiner
Update	Search	9/30/2006	SKK
349	155	9/30/2006	SKK
345	178	9/30/2006	SKK
178	18	9/30/2006	SKK
Update	Search	4/22/2007	SKK
Update	Search	12/17/2007	SKK
345	156-184	12/17/2007	SKK
257	59	12/17/2007	SKK
977	all	12/21/2007	SKK
438	99,347	12/26/2007	SKK
427	58-126.6	12/26/2007	SKK
427	466-486	12/26/2007	SKK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See Interference Search	12/17/2007	SKK	

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Update Search, consulted Lun Yi Lao and Ke Xiao	9/30/2006	SKK
Update Search and consulted Kent CHang	4/24/2007	SKK
Update Search and consulted SPE, Amare Mengistu	12/17/2007	SKK
Consulted Nanotechnology Subject Matter Experts, Matthew Such AU 2891, and Shean Wu AU 1795	12/26/2007	SKK
STIC Nanotechnology Website, and nanotechnology database websites, IEEE, INSPEC, SID, The AMC Portal	12/21/2007	SKK